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Room temperature fabrication of transparent p-NiO/n-ZnO

junctions with tunable electrical properties

Y.B. Wang¹, X.H. Wei¹, L. Chang², D.G. Xu³, B. Dai¹, J.F. Pierson⁴, Y. Wang^{1,*}

¹ State Key Laboratory Cultivation Base for Nonmetal Composites and Functional Materials,

Southwest University of Science and Technology, Mianyang 621010, China.

² China National Machinery Industry Corporation, Beijing 100080, China.

³ Institute of Materials, China Academy of Engineering Physics, Jiangyou 621907, China.

⁴ Institut Jean Lamour, UMR 7198-CNRS, Université de Lorraine, Nancy F-54011, France.

*Corresponding author: Y. Wang

Email: wangyongvlsi@hotmail.com

Tel: +86-816-2419492

Fax: +86-816-2419492

Abstract

Transparent p-n heterojunctions composed of p-NiO and n-ZnO thin films have

been fabricated on indium-tin-oxide (ITO)-coated glass substrates at room

temperature by magnetron sputtering. Various oxygen flow rates have been employed

to the NiO thin films, yielding the tunable resistivity of NiO layers. These p-n

junctions exhibit clear rectifying current-voltage characteristics. Moreover, their

electrical properties can be effectively tuned by the oxygen flow rate to synthesize

NiO layers in these junctions. NiO layer with closely perfect stoichiometry and quite

high resistivity produces better performance in these p-n junctions, including the

small threshold voltage and ideality factor, as well as high rectifying ratio. The

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